

#### **Description**

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#### **Package Marking and Ordering Information**

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
VSM9N65-T2	VSM9N65	TAPING	TO-252	13inch	2500	25000

#### **Absolute Maximum Ratings** (Tc=25℃ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		650	V
$V_{GSS}$	Gate-Source Voltage		±30	V
$I_D$	Continuous Drain Current	T <sub>C</sub> = 25°C	9	Α
		T <sub>C</sub> = 100°C	5.8	Α
I <sub>DM</sub>	Pulsed Drain Current note1		36	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy note2		211	mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C	31	W
Rejc	Thermal Resistance, Junction to Case		4	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient		62.5	°C/W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	$^{\circ}$ C



## **Electrical Characteristics** (T<sub>J</sub>=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units		
Off Characteristic								
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA	650	-	-	V		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	-	-	1	μA		
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±30V	-	-	±100	nA		
On Charac	cteristics							
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	2	3	4	V		
R <sub>DS(on)</sub>	Static Drain-Source on-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =4.5A	-	0.9	1.08	Ω		
Dynamic (	Characteristics							
C <sub>iss</sub>	Input Capacitance	\\ -25\\ \\ -0\\	-	1400	-	pF		
Coss	Output Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V,	-	114	-	pF		
C <sub>rss</sub>	Reverse Transfer Capacitance	f=1.0MHz	-	26	-	pF		
Qg	Total Gate Charge	\/ =F20\/   =0.4	-	32	-	nC		
$Q_{gs}$	Gate-Source Charge	$ V_{DD}$ =520V, $I_{D}$ =9A, $V_{GS}$ =10V	-	5	-	nC		
$Q_gd$	Gate-Drain("Miller") Charge	VGS-10V	-	16	-	nC		
Switching	Characteristics							
t <sub>d(on)</sub>	Turn-on Delay Time		-	23	-	ns		
t <sub>r</sub>	Turn-on Rise Time	V <sub>DD</sub> =325V, I <sub>D</sub> =9A,	-	15	-	ns		
t <sub>d(off)</sub>	Turn-off Delay Time	R <sub>G</sub> =25Ω	-	90	-	ns		
t <sub>f</sub>	Turn-off Fall Time		-	30	-	ns		
Drain-Sou	rce Diode Characteristics and Maxin	num Ratings						
Is	Maximum Continuous Drain to Source Diode Forward Current			-	9	Α		
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	36	Α		
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>SD</sub> =9A	-	-	1.4	٧		
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> =0V, I <sub>S</sub> =9A,	-	310	-	ns		
Q <sub>rr</sub>	Reverse Recovery Charge	di/dt=100A/µs	-	4.1	-	μC		

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition:  $T_J$  = 25°C,  $V_{DD}$  = 50V,  $V_G$  = 10V, L= 10mH,  $I_{AS}$  = 6.5A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤1%



### **Typical Performance Characteristics**

Figure1: Output Characteristics

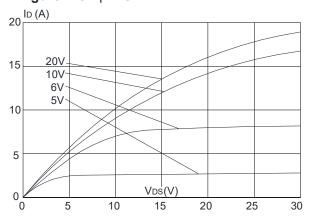


Figure 3:On-resistance vs. Drain Current

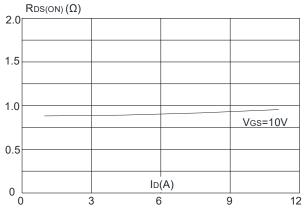


Figure 5: Gate Charge Characteristics

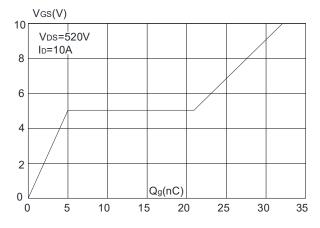


Figure 2: Typical Transfer Characteristics

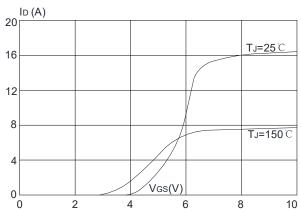


Figure 4: Body Diode Characteristics

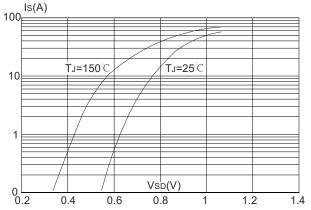
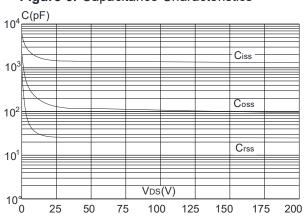


Figure 6: Capacitance Characteristics





**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature

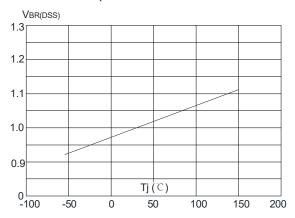
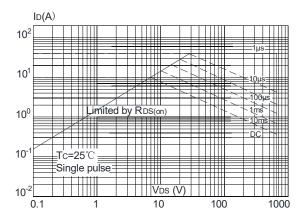
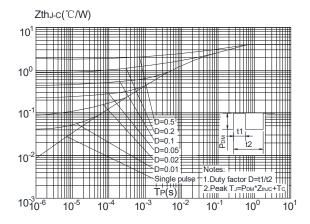


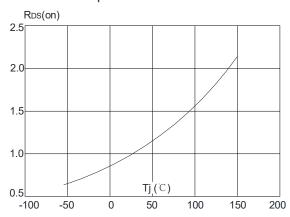
Figure 9: Maximum Safe Operating Area



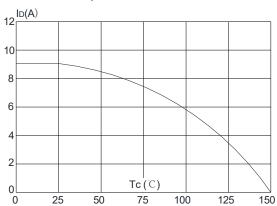
**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Figure 8:** Normalized on Resistance vs. Junction Temperature



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature





#### **Test Circuit**

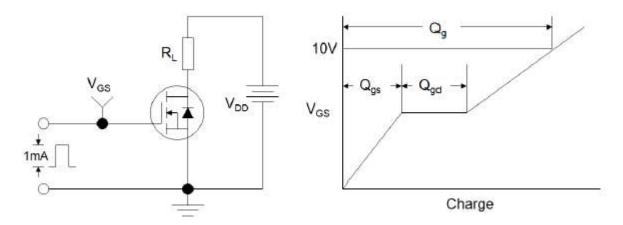


Figure1:Gate Charge Test Circuit & Waveform

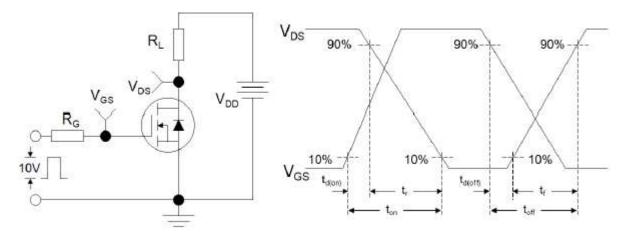


Figure 2: Resistive Switching Test Circuit & Waveforms

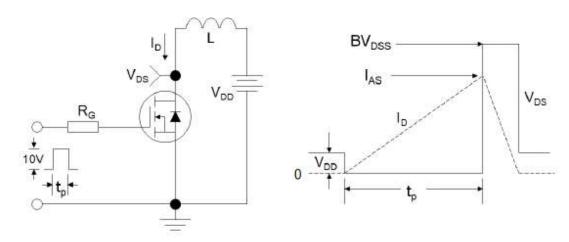


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms